

Issue Classification

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/698,325	REIHL, HEINER	
Examiner	Art Unit	
Hai C. Pham	2861	

ISSUE CLASSIFICATION

ORIGINAL					CROSS REFERENCE(S)								
CLASS		SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
347		236			347	246							
INTERNATIONAL CLASSIFICATION													
B	4	1	J	2/435									
				/									
				/									
				/									
				/									

<p>----- (Assistant Examiner) (Date)</p>		<p><i>Hai Pham</i></p> <p>HAI PHAM PRIMARY EXAMINER (Primary Examiner)</p>		<p>Total Claims Allowed: 8</p>	
<p><i>David Saffa 11/14/05</i> (Legal Instruments Examiner) (Date)</p>		<p><i>11/12/05</i> (Date)</p>		<p>O.G. Print Claim(s) 4</p>	<p>O.G. Print Fig. 3</p>

[illegible]